

<b>Notice of References Cited</b>	Application/Control No. 10/643,636	Applicant(s)/Patent Under Reexamination BUCKLEY, DAVID J.	
	Examiner Huy D. Nguyen	Art Unit 2681	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0158708	08-2003	Frost et al.	702/188
	B	US-2002/0119803	08-2002	Bitterlich et al.	455/552
	C	US-2003/0090528	05-2003	Masuda et al.	345/838
	D	US-6,826,405	11-2004	Doviak et al.	455/445
	E	US-6,690,923	02-2004	Ortiz Perez et al.	455/74.1
	F	US-6,404,775	06-2002	Leslie et al.	370/466
	G	US-6,272,333	08-2001	Smith, Dwight Randall	455/418
	H	US-2002/0068573	06-2002	Raverdy et al.	455/445
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.